Search Notes

Application/Control	No. Applicant(s)/Pate Reexamination	Applicant(s)/Patent under Reexamination	
10/573,264	PELED ET AL.		
Examiner	Art Unit	•	
Son T. Nauven	3643		

SEARCHED					
Class	Subclass	Date	Examiner		
47	20.1 29.4	7/20/2007	STN		
	31 31.1				
	32 32.3				
	58.1R				
	58.1SC				
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		 		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
IPC foreign search, see printouts	7/20/2007	STN		
text search, see printouts	7/20/2007	STN		